

WEST Search History

DATE: Monday, November 01, 2004

<u>Hide?</u>	<u>Set Name</u>	<u>Query</u>	<u>Hit Count</u>
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ</i>			
<input type="checkbox"/>	L9	l3 and L8	12
<input type="checkbox"/>	L8	drift region and resurf	309
<input type="checkbox"/>	L7	l6 and l4	0
<input type="checkbox"/>	L6	(gate insulation film or gate stack or gate insulator of gate insulating film) same (perpendicular or perpendicularly)	252
<input type="checkbox"/>	L5	(gate insulation film or gate stack or gate insulator) same (perpendicular or perpendicularly)	464
<input type="checkbox"/>	L4	l1 and l2 and L3	15
<input type="checkbox"/>	L3	drift region same (perpendicular or perpendicularly) same concentration	39
<input type="checkbox"/>	L2	base region same (perpendicular or perpendicularly)	648
<input type="checkbox"/>	L1	(semiconductor or silicon) (wafer or substrate)	446880

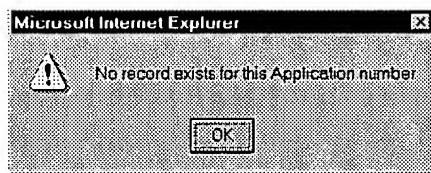
END OF SEARCH HISTORY

11/1/04 Craig A. Thompson

Electronic Information Disclosure Statement

US Document Identifiers Search Page

Application Number



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